

STANFORD UNIVERSITY
DEPARTMENT OF STATISTICS
DEPARTMENTAL SEMINAR

4:15 p.m., Tuesday, April 19, 2005
Sequoia Hall Room 200
(Cookies at 3:45 in 1st Floor Lounge)

Fugee Tsung

Department of Industrial Engineering and Engineering Management
Hong Kong University of Science & Technology

Recent Advances in Statistical Quality Control

Abstract:

As quality and Six Sigma excellence has become a decisive factor in global market competition, quality control techniques such as Statistical Process Control (SPC) and Engineering Process Control (EPC) are becoming popular in industries. With advances in information, sensing, and data capture technology, large volumes of data are being routinely collected and shared over multiple-stage processes, which has a growing impact on the existing SPC and EPC methods. This talk will discuss several technical challenges and present some recent extensions in this area such as profile monitoring, engineering-controlled process monitoring, and multistage SPC.

Bio: Dr. Fugee Tsung is an associate professor in the Department of Industrial Engineering and Engineering Management at the Hong Kong University of Science & Technology. He received both his M.S. and Ph.D. in Industrial and Operations Engineering from the University of Michigan, Ann Arbor, and his B.S. degree in Mechanical Engineering from National Taiwan University. He worked for Ford Motors and Rockwell International and did his post-doctoral research with Chrysler. He is now a Department Editor for the IIE Transactions on Quality and Reliability, Associate Editor for IJRQSE and IJSSCA, and Chairing the Quality, Statistics, and Reliability (QSR) Section at INFORMS. He is also the winner of the Best Paper Award for the IIE Transactions focus issue on Quality and Reliability in 2003. His current research interests include quality engineering and management, statistical process control, monitoring and diagnosis.